

Notice of References Cited	Application/Control No. 10/533,915	Applicant(s)/Patent Under Reexamination ZAMA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,519,235 A	05-1996	Ramesh, Ramamoorthy	257/295
*	B	US-2001/0026468 A1	10-2001	Tanikawa, Akio	365/151
*	C	US-2003/0041444 A1	03-2003	Debe et al.	29/623.1
*	D	US-6,565,763 B1	05-2003	Asakawa et al.	216/56
*	E	US-2003/0212306 A1	11-2003	Banik, Michael S.	600/30
*	F	US-2003/0224132 A1	12-2003	Han, Chien-Chung	428/36.9
*	G	US-2003/0222048 A1	12-2003	Asakawa et al.	216/2
*	H	US-2004/0001991 A1	01-2004	Kinkelaar et al.	429/38
*	I	US-2004/0214352 A1	10-2004	Kijima et al.	438/003
*	J	US-2005/0122005 A1	06-2005	Higuchi et al.	310/363
*	K	US-2006/0124470 A1	06-2006	Zama et al.	205/317
*	L	US-7,090,784 B2	08-2006	Asakawa et al.	216/41
*	M	US-7,097,781 B2	08-2006	Asakawa et al.	216/56

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,808,481 A	02-1989	Luxon, Bruce A.	428/407
*	B	US-5,316,830 A	05-1994	Adams et al.	428/195.1
*	C	US-5,666,305 A	09-1997	Mihara et al.	365/145
*	D	US-5,705,265 A	01-1998	Clough et al.	428/307.3
*	E	US-6,060,327 A	05-2000	Keen, Randy E.	204/403.14
*	F	US-6,205,016 B1	03-2001	Niu, Chun-Ming	361/503
*	G	US-6,326,215 B1	12-2001	Keen, Randy E.	436/518
*	H	US-6,491,789 B2	12-2002	Niu, Chun-Ming	162/145
*	I	US-6,579,754 B2	06-2003	Suenaga et al.	438/240
*	J	US-2004/0038251 A1	02-2004	Smalley et al.	435/6
*	K	US-6,699,667 B2	03-2004	Keen, Randy E.	435/6
*	L	US-2006/0088731 A1	04-2006	Kijima et al.	428/701
*	M	US-2006/0083933 A1	04-2006	Kijima et al.	428/432

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,948,685 A	08-1990	Ohsawa et al.	429/213
*	B	US-6,515,957 B1	02-2003	Newns et al.	369/126
*	C	US-6,636,433 B2	10-2003	Tanikawa, Akio	365/36
*	D	US-2005/0095389 A1	05-2005	Newns, Dennis M.	428/064.4
*	E	US-6,914,105 B1	07-2005	Charpentier et al.	526/67
*	F	US-2006/0076540 A1	04-2006	Zama et al.	252/500
*	G	US-7,065,033 B2	06-2006	Onoe et al.	369/126
*	H	US-7,074,484 B2	07-2006	Topolkaraev et al.	428/411.1
*	I	US-2006/0275660 A1	12-2006	Zama et al.	429/213
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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